

SEMiX155GD17E4



SEMiX® 5

Trench IGBT Modules

SEMiX155GD17E4

Target Data

Features

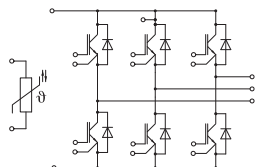
- Solderless assembling solution with PressFIT signal pins and screw power terminals
- IGBT 4 Trench Gate Technology
- $V_{CE(sat)}$ with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and reliable internal connections
- Extended Operation Temperature $T_{jop} = 150^\circ\text{C}$
- UL recognized file no. E63532
- NTC temperature sensor inside

Typical Applications*

- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Dynamic data are estimated
- Product reliability results are valid for $T_{jop} = 150^\circ\text{C}$
- Case temperature limited to $T_c = 125^\circ\text{C}$ max.
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"



GD

Absolute Maximum Ratings

Symbol	Conditions	Values	Unit
IGBT			
V_{CES}	$T_j = 25^\circ\text{C}$	1700	V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	245
		$T_c = 80^\circ\text{C}$	186
I_{Cnom}		150	A
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$	450	A
V_{GES}		-20 ... 20	V
t_{psc}	$V_{CC} = 1000\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 1700\text{ V}$	$T_j = 150^\circ\text{C}$	10
			μs
T_j		-40 ... 175	$^\circ\text{C}$

Inverse diode

V_{RRM}	$T_j = 25^\circ\text{C}$	1700	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	175
		$T_c = 80^\circ\text{C}$	130
I_{Fnom}		150	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	300	A
I_{FSM}	$t_p = 10\text{ ms}$, $\sin 180^\circ$, $T_j = 25^\circ\text{C}$	918	A
T_j		-40 ... 175	$^\circ\text{C}$

Module

$I_{t(RMS)}$		300	A
T_{stg}	module without TIM	-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$	4000	V

Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$V_{CE(sat)}$	$I_C = 150\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.90	2.20	V
		$T_j = 150^\circ\text{C}$	2.25	2.45	V
V_{CE0}	chipelevel	$T_j = 25^\circ\text{C}$	1.10	1.20	V
		$T_j = 150^\circ\text{C}$	1.00	1.10	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	5.3	6.7	$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	8.3	9.0	$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}$, $I_C = 6\text{ mA}$	5.2	5.8	6.4	V
I_{CES}	$V_{GE} = 0\text{ V}$, $V_{CE} = 1700\text{ V}$, $T_j = 25^\circ\text{C}$			2.0	mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	12.0		nF
C_{oes}		$f = 1\text{ MHz}$	0.50		nF
C_{res}		$f = 1\text{ MHz}$	0.38		nF
Q_G	$V_{GE} = -8\text{ V} \dots +15\text{ V}$		1200		nC
R_{Gint}	$T_j = 25^\circ\text{C}$		5.0		Ω
$t_{d(on)}$	$V_{CC} = 1200\text{ V}$ $I_C = 150\text{ A}$ $V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$	t.b.d.		ns
t_r		$T_j = 150^\circ\text{C}$	t.b.d.		ns
E_{on}	$T_j = 150^\circ\text{C}$	$T_j = 150^\circ\text{C}$	t.b.d.		mJ
$t_{d(off)}$		$T_j = 150^\circ\text{C}$	t.b.d.		ns
t_f		$T_j = 150^\circ\text{C}$	t.b.d.		ns
E_{off}		$T_j = 150^\circ\text{C}$	t.b.d.		mJ
$R_{th(j-c)}$	per IGBT			0.18	K/W
$R_{th(c-s)}$	per IGBT ($\lambda_{grease} = 0.81\text{ W/mK}$, thickness 50-100 μm)		t.b.d.		K/W
$R_{th(c-s)}$	per IGBT ($\lambda = 3.4\text{ W/mK}$)		t.b.d.		K/W



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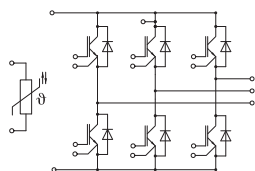
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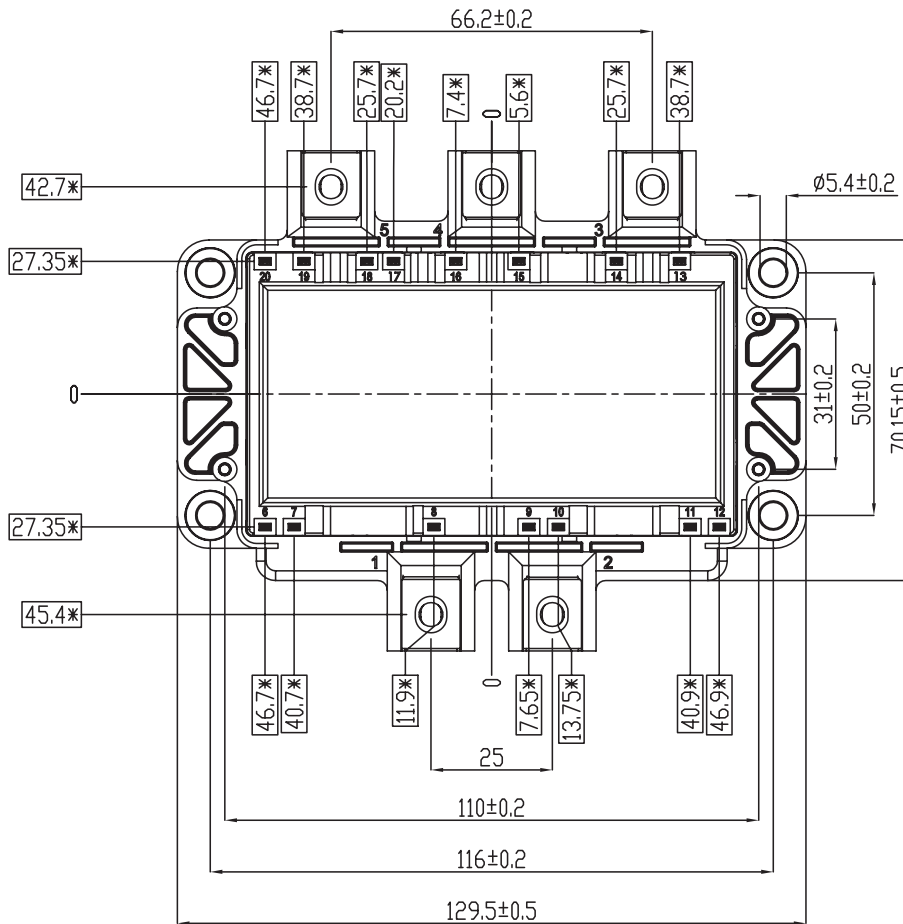
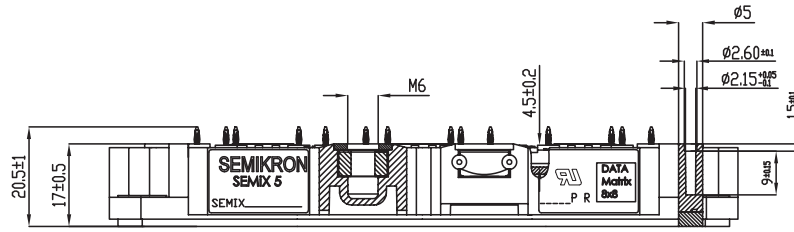
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Inverse diode						
$V_F = V_{EC}$	$I_F = 150\text{ A}$ $V_{GE} = 0\text{ V}$ chipllevel	$T_j = 25^{\circ}\text{C}$		2.00	2.40	V
		$T_j = 150^{\circ}\text{C}$		2.14	2.56	V
V_{F0}	chipllevel	$T_j = 25^{\circ}\text{C}$		1.32	1.56	V
		$T_j = 150^{\circ}\text{C}$		1.08	1.22	V
r_F	chipllevel	$T_j = 25^{\circ}\text{C}$		4.5	5.6	m Ω
		$T_j = 150^{\circ}\text{C}$		7.1	9.0	m Ω
I_{RRM}	$I_F = 150\text{ A}$	$T_j = 150^{\circ}\text{C}$		-		A
Q_{rr}	$V_{GE} = -15\text{ V}$ $V_{CC} = 1200\text{ V}$	$T_j = 150^{\circ}\text{C}$		-		μC
E_{rr}		$T_j = 150^{\circ}\text{C}$				mJ
$R_{th(j-c)}$	per diode				0.32	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease} = 0.81\text{ W/mK}$, thickness 50-100 μm)			t.b.d.		K/W
$R_{th(c-s)}$	per diode ($\lambda = 3.4\text{ W/mK}$)			t.b.d.		K/W
Module						
L_{CE}				38		nH
R_{CC+EE}	measured per switch	$T_C = 25^{\circ}\text{C}$		1.2		m Ω
		$T_C = 125^{\circ}\text{C}$		1.65		m Ω
$R_{th(c-s)1}$	calculated without thermal coupling			t.b.d.		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module ($\lambda_{grease} = 0.81\text{ W/}$ (m°K))			t.b.d.		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module, pre-applied phase change material			t.b.d.		K/W
M_s	to heat sink (M5)		3		6	Nm
M_t		to terminals (M6)	3		6	Nm
						Nm
w				398		g
Temperature Sensor						
R_{100}	$T_C = 100^{\circ}\text{C}$ ($R_{25} = 5\text{ k}\Omega$)			$493 \pm 5\%$		Ω
$B_{100/125}$	$R_{(T)} = R_{100} \exp[B_{100/125}(1/T - 1/T_{100})]$; $T[\text{K}]$;			3550 $\pm 2\%$		K

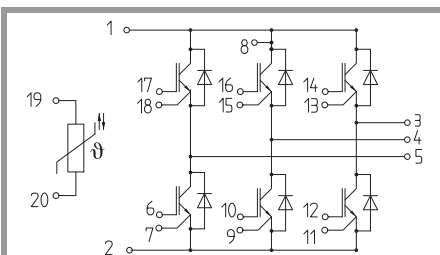
SEMiX155GD17E4



* = All dimension with tolerance of $\begin{matrix} \oplus \\ \ominus \end{matrix} \begin{matrix} \oplus \\ \ominus \end{matrix} 0,4$

For technical details please refer to SEMiX(R)5 Mounting Instruction

SEMiX5p



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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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